

ABSTRACT

Disclosed is a probe card for a power semiconductor for high voltage and high current, the probe card being capable of providing uniform pin force and preventing an arc. According to one aspect of the present invention, the probe card for a power semiconductor for high voltage and high current may comprise: a PCB having a through-hole formed on one side thereof so that multiple probe pins pass therethrough and come into contact with a terminal of an object to be tested, thereby forming a test space in which a test is performed; and a pin insert block which is disposed in the through-hole of the PCB and in which a portion of each of the plurality of probe pins is fixed and supported, wherein the plurality of probe pins are fixed to the pin insert block such that each end of the plurality of probe pins coming into contact with the terminal is disposed at the same height.

FIG. 6